## **DATA SHEET**



# MOS FIELD EFFECT TRANSISTOR

NP40N055EHE, NP40N055KHE NP40N055CHE, NP40N055DHE, NP40N055MHE, NP40N055NHE

# **SWITCHING N-CHANNEL POWER MOS FET**

#### **DESCRIPTION**

These products are N-channel MOS Field Effect Transistors designed for high current switching applications.

### ORDERING INFORMATION

PART NUMBER	LEAD PLATING	PACKING	PACKAGE		
NP40N055EHE-E1-AY Note1, 2			TO 202 (MD 257 I) has 4.4 a		
NP40N055EHE-E2-AY Note1, 2	Dura Ca (Tia) Tana 200 a (saal		TO-263 (MP-25ZJ) typ. 1.4 g		
NP40N055KHE-E1-AY Note1	Pure Sn (Tin)	Tape 800 p/reel	TO-263 (MP-25ZK) typ. 1.5 g		
NP40N055KHE-E2-AY Note1					
NP40N055CHE-S12-AZ Note1, 2	Sn-Ag-Cu		TO-220 (MP-25) typ. 1.9 g		
NP40N055DHE-S12-AY Note1, 2		T. b = 50 = #b =	TO-262 (MP-25 Fin Cut) typ. 1.8 g		
NP40N055MHE-S18-AY Note1	Pure Sn (Tin)	Tube 50 p/tube		TO-220 (MP-25K) typ. 1.9 g	
NP40N055NHE-S18-AY Note1			TO-262 (MP-25SK) typ. 1.8 g		

Notes 1. Pb-free (This product does not contain Pb in the external electrode.)

2. Not for new design

## **FEATURES**

- Channel temperature 175 degree rated
- Super low on-state resistance

 $R_{DS(on)} = 23 \text{ m}\Omega$  MAX. (Vgs = 10 V, ID = 20 A)

• Low input capacitance

Ciss = 1070 pF TYP.

• Built-in gate protection diode

(TO-220)



(TO-262)





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Not all products and/or types are available in every country. Please check with an NEC Electronics

sales representative for availability and additional information.



## ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (Vgs = 0 V)	VDSS	55	V
Gate to Source Voltage (V <sub>DS</sub> = 0 V)	Vgss	±20	V
Drain Current (DC) (Tc = 25°C)	I <sub>D(DC)</sub>	±40	Α
Drain Current (Pulse) Note1	ID(pulse)	±100	Α
Total Power Dissipation (T <sub>A</sub> = 25°C)	Рт	1.8	W
Total Power Dissipation (Tc = 25°C)	Рт	66	W
Channel Temperature	Tch	175	°C
Storage Temperature	Tstg	-55 to +175	°C
Single Avalanche Current Note2	las	29/21/7	Α
Single Avalanche Energy Note2	Eas	0.8/44/49	mJ

**Notes 1.** PW  $\leq$  10  $\mu$ s, Duty cycle  $\leq$  1%

2. Starting T<sub>ch</sub> = 25°C, V<sub>DD</sub> = 28 V, R<sub>G</sub> = 25  $\Omega$ , V<sub>GS</sub> = 20  $\rightarrow$  0 V (See Figure 4.)

### THERMAL RESISTANCE

Channel to Case Thermal Resistance	Rth(ch-C)	2.27	°C/W
Channel to Ambient Thermal Resistance	Rth(ch-A)	83.3	°C/W

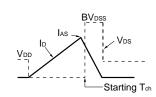


### **ELECTRICAL CHARACTERISTICS (TA = 25°C)**

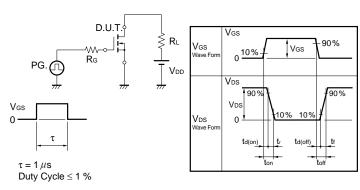
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 20 A		18	23	mΩ
Gate to Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2.0	3.0	4.0	٧
Forward Transfer Admittance	<b>y</b> fs	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 20 A	7	14		S
Drain Leakage Current	IDSS	V <sub>DS</sub> = 55 V, V <sub>GS</sub> = 0 V			10	μΑ
Gate to Source Leakage Current	Igss	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V			±10	μΑ
Input Capacitance	Ciss	V <sub>DS</sub> = 25 V,		1070	1610	pF
Output Capacitance	Coss	V <sub>GS</sub> = 0 V,		190	280	pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		95	180	pF
Turn-on Delay Time	t <sub>d(on)</sub>	I <sub>D</sub> = 20 A,		16	35	ns
Rise Time	tr	V <sub>GS</sub> = 10 V,		9.2	23	ns
Turn-off Delay Time	t <sub>d(off)</sub>	V <sub>DD</sub> = 28 V,		29	57	ns
Fall Time	t <sub>f</sub>	$R_G = 1 \Omega$		9.2	23	ns
Total Gate Charge	QG	I <sub>D</sub> = 40 A,		23	35	nC
Gate to Source Charge	Qgs	$V_{DD} = 44 V$ ,		6		nC
Gate to Drain Charge	Q <sub>GD</sub>	V <sub>GS</sub> = 10 V		9		nC
Body Diode Forward Voltage	V <sub>F(S-D)</sub>	I <sub>F</sub> = 40 A, V <sub>GS</sub> = 0 V		1.0		V
Reverse Recovery Time	trr	I <sub>F</sub> = 40 A, V <sub>GS</sub> = 0 V,		38		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		46		nC

### TEST CIRCUIT 1 AVALANCHE CAPABILITY

# $\begin{array}{c} \text{D.U.T.} \\ \text{Rg} = 25 \ \Omega \\ \text{VGS} = 20 \rightarrow 0 \ V \\ \end{array} \begin{array}{c} \text{PG.} \\ \text{W} \\ \text{W} \end{array} \begin{array}{c} \text{S} \\ \text{50} \ \Omega \\ \text{W} \end{array} \begin{array}{c} \text{VDD} \\ \text{W} \end{array}$



# TEST CIRCUIT 2 SWITCHING TIME



### **TEST CIRCUIT 3 GATE CHARGE**

### TYPICAL CHARACTERISTICS (TA = 25°C)

Figure 1. DERATING FACTOR OF FORWARD BIAS SAFE OPERATING AREA

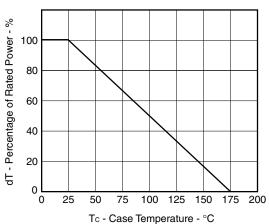


Figure.3 FORWARD BIAS SAFE OPERATING AREA

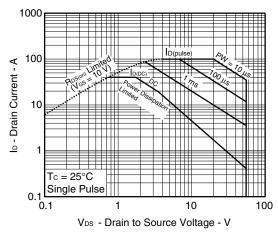


Figure2. TOTAL POWER DISSIPATION vs. CASE TEMPERATURE

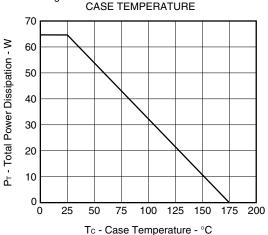


Figure 4. SINGLE AVALANCHE ENERGY DERATING FACTOR

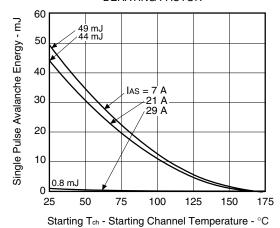


Figure 5. TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

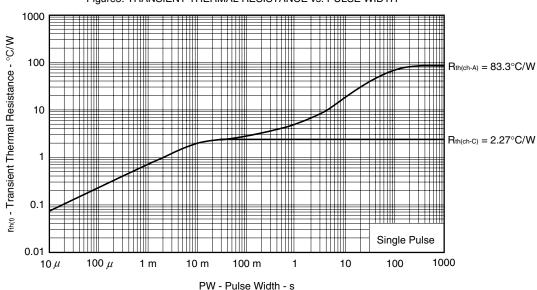


Figure 6. FORWARD TRANSFER CHARACTERISTICS

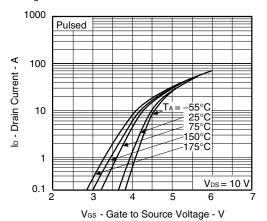


Figure8. FORWARD TRANSFER ADMITTANCE vs. **DRAIN CURRENT** 

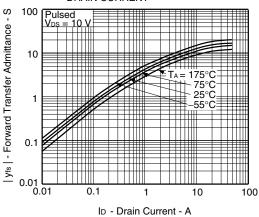


Figure 10. DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT  $\mathsf{Rps}_{(on)}$  - Drain to Source On-state Resistance -  $\mathsf{m}\Omega$ 50 Pulsed 40 30  $V_{GS} = 10 \text{ V}$ 20 10 0 10 100 0.1 ID - Drain Current - A

Figure 7. DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE

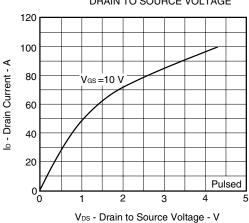


Figure9. DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

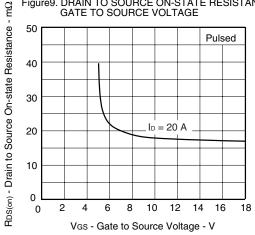
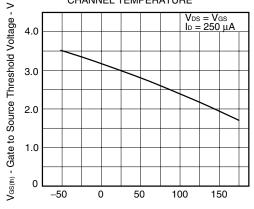
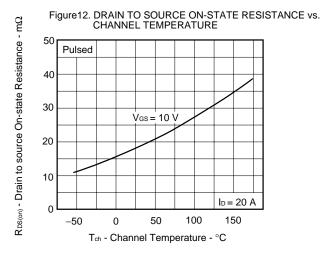
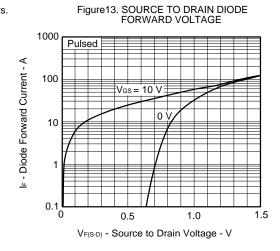


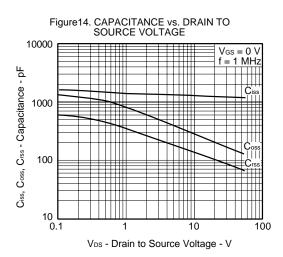
Figure 11. GATE TO SOURCE THRESHOLD VOLTAGE vs. CHANNEL TEMPERATURE

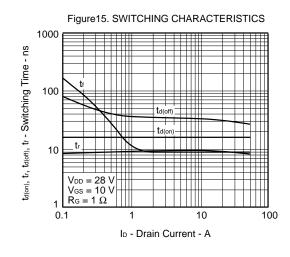


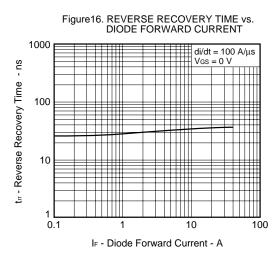
Tch - Channel Temperature - °C

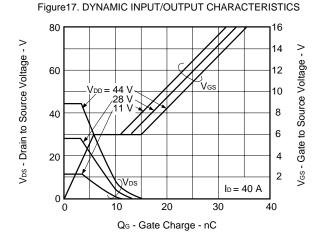




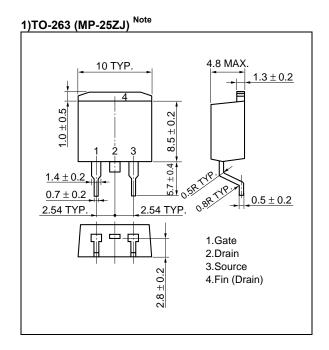


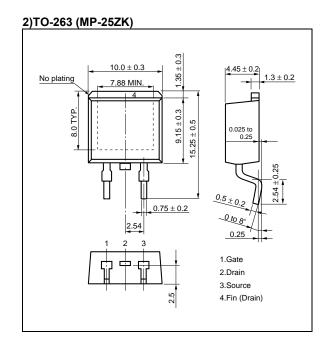


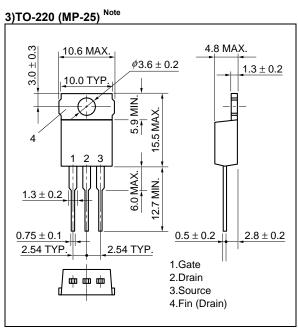


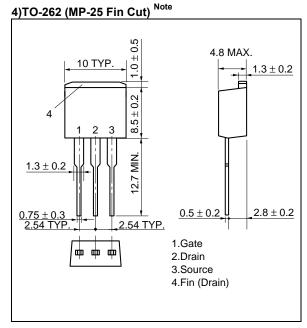


### <R> PACKAGE DRAWINGS (Unit: mm)

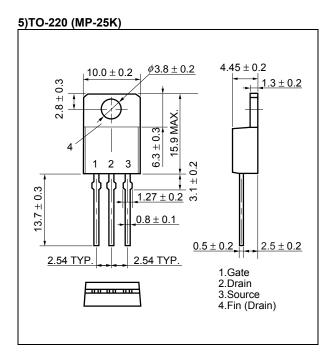


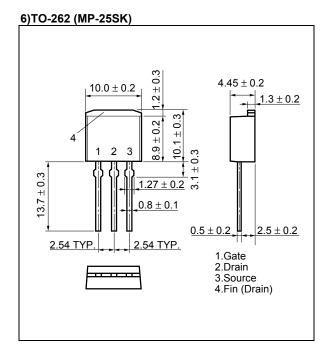




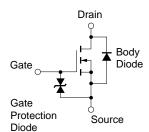


Note Not for new design





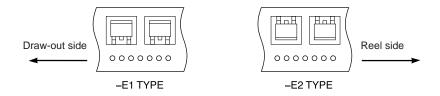
### **EQUIVALENT CIRCUIT**



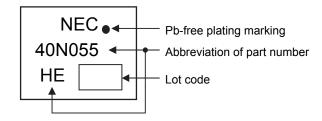
**Remark** The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

### <R> TAPE INFORMATION

There are two types (-E1, -E2) of taping depending on the direction of the device.



### <R> MARKING INFORMATION



## <R> RECOMMENDED SOLDERING CONDITIONS

These products should be soldered and mounted under the following recommended conditions.

For soldering methods and conditions other than those recommended below, please contact an NEC Electronics sales representative.

For technical information, see the following website.

Semiconductor Device Mount Manual (http://www.necel.com/pkg/en/mount/index.html)

Soldering Method	Soldering Conditions	Recommended Condition Symbol	
Infrared reflow	Maximum temperature (Package's surface temperature): 260°C or below		
MP-25ZJ, MP-25ZK	Time at maximum temperature: 10 seconds or less		
	Time of temperature higher than 220°C: 60 seconds or less	ID00 00 0	
	Preheating time at 160 to 180°C: 60 to 120 seconds	IR60-00-3	
	Maximum number of reflow processes: 3 times		
	Maximum chlorine content of rosin flux (percentage mass): 0.2% or less		
Wave soldering	Maximum temperature (Solder temperature): 260°C or below		
MP-25, MP-25K, MP-25SK,	Time: 10 seconds or less	THDWS	
MP-25 Fin Cut	Maximum chlorine content of rosin flux: 0.2% (wt.) or less		
Partial heating	Maximum temperature (Pin temperature): 350°C or below		
MP-25ZJ, MP-25ZK,	Time (per side of the device): 3 seconds or less	P350	
MP-25K, MP-25SK	Maximum chlorine content of rosin flux: 0.2% (wt.) or less		
Partial heating	Maximum temperature (Pin temperature): 300°C or below		
MP-25, MP-25 Fin Cut	Time (per side of the device): 3 seconds or less	P300	
	Maximum chlorine content of rosin flux: 0.2% (wt.) or less		

Caution Do not use different soldering methods together (except for partial heating).

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